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TEST REPORT

Application No.: BTEK240819010AE

Applicant: SHENZHEN ECARE ELECTRONICS CO., LTD

Address of Applicant: B201/B401/B501/B601, Hua Li Industrial Building, 404 Yu An Road, Bao An,

Shenzhen, Guang Dong, China

Manufacturer: SHENZHEN ECARE ELECTRONICS CO., LTD

Address of Manufacturer: B201/B401/B501/B601, Hua Li Industrial Building, 404 Yu An Road, Bao An,

Shenzhen, Guang Dong, China

Equipment Under Test (EUT):

EUT Name: Bluetooth thermometer & hygrometer

Test Model.: TP351

Adding Model(s): TP351W,C51

Trade Mark: /

FCC ID: 2AATP-TP351

Standard(s): 47 CFR Part 2 Subpart J Section 2.1093

447498 D01 General RF Exposure Guidance v06

Date of Receipt: 2024-08-20

Date of Test: 2024-08-21 to 2024-08-30

Date of Issue: 2024-09-01

Test Result: Pass*

Ción Car

Lion Cai/ Approved & Authorized EMC Laboratory Manager

ShenZhen BANTEK Testing Co.,Ltd.

Add: A5&A6, Building B1&B2, No.45 Gangtou Road, Bogang Community, Shajing Street

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^{*} In the configuration tested, the EUT complied with the standards specified above.



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Revision Record				
Version	Chapter	Date	Modifier	Remark
V0		2024-09-01		Original
	0		0	

Authorized for issue by:		
BTEX 3	Zora . Huang Zora Huang/Project Engineer	
0	June Li	
	June Li/Reviewer	0 0

Remarks:

The results shown in this test report refer only to the sample(s) tested, this test report cannot be reproduced, except in full, without prior written permission of the company. The report would be invalid without specific stamp of test institute and the signatures of compiler and approver.

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General Information

3.1 Details of E.U.T.

Power supply:	DC 3V
Frequency Range:	2402MHz to 2480MHz
Bluetooth Version:	V5.1 BLE
Modulation Type:	GFSK
Number of Channels:	40
Channel Spacing:	PCB Antenna
Antenna Type:	0dBi
Antenna Gain:	BTEK240819010AE-01
Sample No.:	GFSK

Remark: The information in this section is provided by the applicant or manufacturer, BANTEK is not liable to the accuracy, suitability, reliability or/and integrity of the information.

Model No.:TP351,TP351W,C51

Only the model TP351 was tested. According to the declaration from the applicant, the electrical circuit design, layout, components used, internal wiring and functions of other models are identical for the above models, with only difference on Model No.

3.2 Description of Support Units

Ì	Description	Manufacturer	Model No.	Serial No.
	1		11	The state of the s

3.3 Test Location

All tests were performed at:

Shenzhen BANTEK Testing Co., Ltd.,

A5&A6, Building B1&B2, No.45 Gangtou Road, Bogang Community, Shajing Street, Bao'an District,

Shenzhen, Guangdong, China 518103

Tel:0755-2334 4200 Fax: 0755-2334 4200

FCC Registration Number: 264293 Designation Number: CN1356 No tests were sub-contracted.

3.4 Deviation from Standards

None

3.5 Abnormalities from Standard Conditions

None

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4 Test Requirement

KDB447498 D01 General RF Exposure Guidance v06, Clause 4.3.1(b)

[(max. power of channel, including tune-up tolerance, mW) / (min. test separation distance, mm)] • $[\sqrt{f(GHz)}] \le 3.0$

Where

- -f(GHz) is the RF channel transmit frequency in GHz
- -Power and distance are rounded to the nearest mW and mm before calculation
- -The test exclusions are applicable only when the minimum test separation distance is \leq 50 mm, and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is \leq 5 mm, a distance of 5 mm according to 4.1 f) is applied to determine SAR test exclusion.

4.1Assessment Result

□ Passed

■ Not Applicable

Туре	Frequency (MHz)	Conducted Power (dBm)	Maximum Tune-up (dBm)	Calculating data	Limit	Result
BLE	2402	3.62	4	0.78	1.0	Pass

Note: The exposure evaluation safety distance is 5mm.

- End of the Report -

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